

STW60NM50N

N-channel 500 V, 0.035 Ω, 68 A, MDmesh™ II Power MOSFET in a TO-247 package

Datasheet - production data

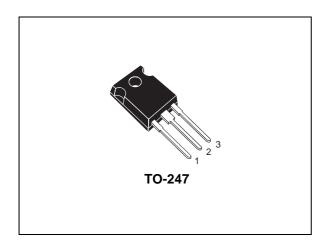
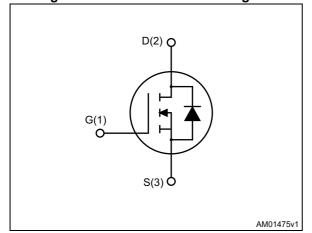


Figure 1. Internal schematic diagram



Features

Order code V _{DSS} (@T _{jmax})		R _{DS(on) max}	I _D
STW60NM50N	550 V	<0.043 Ω	68 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

· Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

Order codes	Marking	Packages	Packaging
STW60NM50N 60NM50N		TO-247	Tube

Contents STW60NM50N

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STW60NM50N Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate- source voltage	±25	V
I _D	Drain current (continuous) at T _C = 25 °C	68	Α
I _D	Drain current (continuous) at T _C = 100 °C	43	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	272	Α
P _{TOT}	Total dissipation at T _C = 25 °C	446	W
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	-55 to 150	°C
T _j	Max. operating junction temperature	150	°C

^{1.} Pulse width limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	0.28	°C/W
R _{thj-amb} Thermal resistance junction-ambient max		50	°C/W

Table 4. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AS}	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{j\;Max}$)	11	А
E _{AS}	Single pulse avalanche energy (starting Tj=25 °C, I _D =I _{AS} , V _{DD} =50 V)	551	mJ

^{2.} $I_{SD} \leq$ 68 A, di/dt \leq 400 A/ μ s, V_{DD} =80% $V_{(BR)DSS}$

Electrical characteristics STW60NM50N

2 Electrical characteristics

(T_{CASE}=25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0$, $I_D = 1$ mA	500			V
I _{DSS}	Zero gate voltage drain current	$V_{GS} = 0$, $V_{DS} = 500 \text{ V}$ $V_{GS} = 0$, $V_{DS} = 500 \text{ V}$, $T_j = 125 \text{ °C}$			1 100	μΑ
I _{GSS}	Gate-body leakage current	$V_{DS} = 0, V_{GS} = \pm 20 \text{ V}$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2	3	4	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 34 A		0.035	0.043	Ω

Table 6. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	5790	-	pF
C _{oss}	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	365	-	pF
C _{rss}	Reverse transfer capacitance	$V_{GS} = 0$	-	14	-	pF
C _{oss eq.} (1)	Equivalent output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{V to } 480 \text{ V}$	-	1008	-	pF
Qg	Total gate charge	V _{DD} = 480 V, I _D = 68 A, V _{GS} = 10 V	-	178	-	nC
Q_{gs}	Gate-source charge		-	28	-	nC
Q _{gd}	Gate-drain charge	(see Figure 14)	-	95	-	nC
R _g	Gate input resistance	f=1 MHz gate DC bias=0 Test signal level = 20 mV open drain	-	2	-	Ω

^{1.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS}

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time		-	206	-	ns
t _r	Rise time	$V_{DD} = 300 \text{ V}, I_{D} = 32.5 \text{ A}$ $R_{G} = 4.7 \Omega V_{GS} = 10 \text{ V}$	-	36	-	ns
t _{d(off)}	Turn-off delay time	(see Figure 13)	-	40	-	ns
t _f	Fall time		-	27.5	-	ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		68	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		272	Α
V _{SD} (2)	Forward on voltage	I _{SD} = 68 A, V _{GS} = 0	-		1.6	٧
t _{rr}	Reverse recovery time	I _{SD} = 68 A, di/dt = 100 A/μs	-	476		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 100 V	-	10.5		nC
I _{RRM}	Reverse recovery current	(see Figure 15)	-	44		Α
t _{rr}	Reverse recovery time	I _{SD} = 68 A, di/dt = 100 A/μs	-	586		ns
Q _{rr}	Reverse recovery charge	$V_{DD} = 100 \text{ V}, T_j = 150 ^{\circ}\text{C}$	-	15		nC
I _{RRM}	Reverse recovery current	(see Figure 15)	-	51		Α

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: Pulse duration = $300 \mu s$, duty cycle 1.5%

Electrical characteristics STW60NM50N

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance

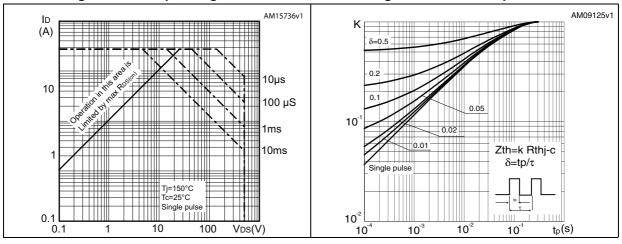


Figure 4. Output characteristics

Figure 5. Transfer characteristics

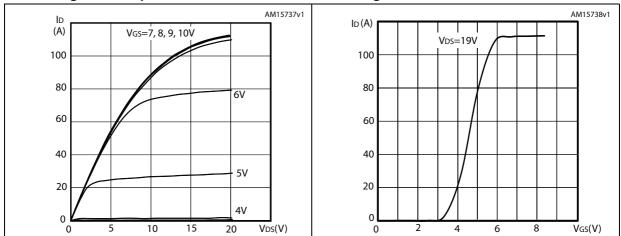


Figure 6. Normalized $V_{(BR)DSS}$ vs temperature

Figure 7. Static drain-source on-resistance

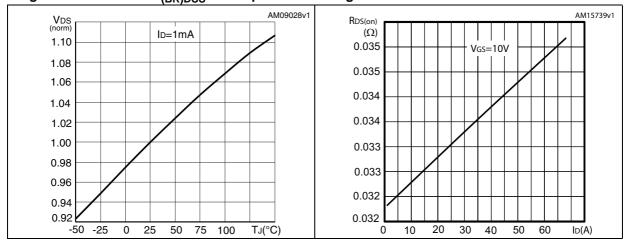


Figure 8. Gate charge vs gate-source voltage

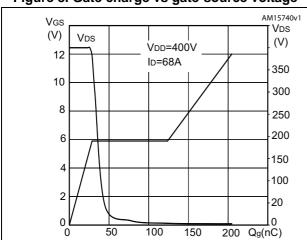


Figure 9. Capacitance variations

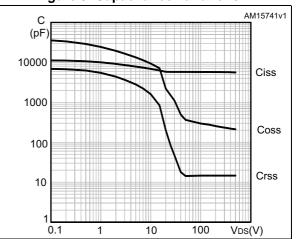
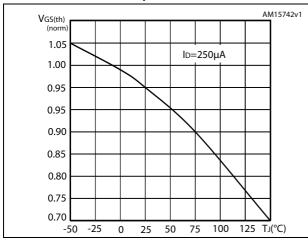


Figure 10. Normalized gate threshold voltage vs temperature

Figure 11. Normalized on-resistance vs temperature



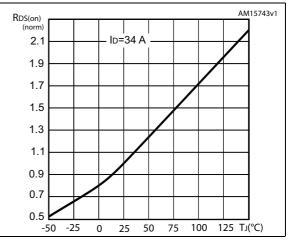
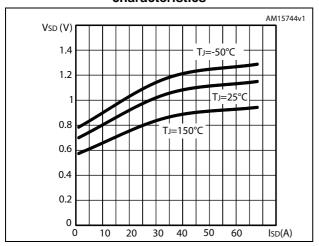


Figure 12. Source-drain diode forward characteristics



Test circuits STW60NM50N

3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

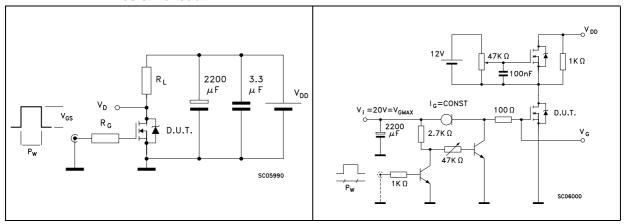


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped Inductive load test circuit

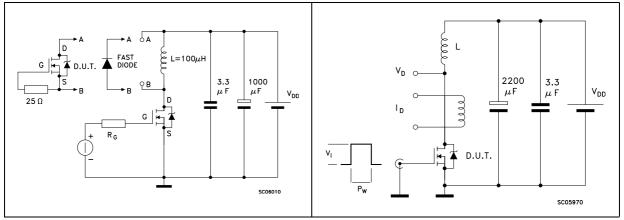
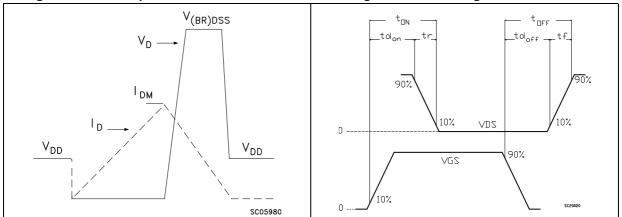


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform



4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.



Table 9. TO-247 mechanical data

Dim		mm.	
Dim.	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

HEAT-SINK PLANE

BACK VIEW 0075325, G

Figure 19. TO-247 drawing

Revision history STW60NM50N

5 Revision history

Table 10. Document revision history

Date	Revision	Changes
26-Apr-2012	1	First release.
16-Apr-2013	2	 Inserted: Section 2.1: Electrical characteristics (curves) Modified: I_{AS} value on Table 4 Minor text changes

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